



QUAD DIGITAL ISOLATORS

FEATURES

- 1, 25, and 150-Mbps Signaling Rate Options
 - Low Channel-to-Channel Output Skew;
 1 ns Max
 - Low Pulse-Width Distortion (PWD);
 2 ns Max
 - Low Jitter Content; 1 ns Typ at 150 Mbps
- Typical 25-Year Life at Rated Working Voltage (see application note SLLA197 and Figure 14)
- 4000-V_{peak} Isolation, 560-V_{peak} Working Voltage
- UL 1577 Certified
- 4 kV ESD Protection
- Operate With 3.3-V or 5-V Supplies

DESCRIPTION

- High Electromagnetic Immunity (see application report SLLA181)
- -40°C to 125°C Operating Range

APPLICATIONS

- Industrial Fieldbus
- Computer Peripheral Interface
- Servo Control Interface
- Data Acquisition

The ISO7240, ISO7241 and ISO7242 are quad-channel digital isolators with multiple channel configurations with output enable function. These devices have logic input and output buffers separated by TI's silicon dioxide (SiO_2) isolation barrier. Used in conjunction with isolated power supplies, these devices block high voltage, isolate grounds, and prevent noise currents from entering the local ground and interfering with or damaging sensitive circuitry.

The ISO7240 has all four channels in the same direction while the ISO7241 has three channels the same direction and one channel in opposition. The ISO7242 has two channels in each direction.

The A and C option devices have TTL input thresholds and a noise-filter at the input that prevents transient pulses from being passed to the output of the device. The M option devices have CMOS Vcc/2 input thresholds and do not have the input noise-filter or the additional propagation delay.

A periodic update pulse is sent across the barrier to ensure the proper dc level of the output. If this dc-refresh pulse is not received, the input is assumed to be unpowered or not being actively driven, and the failsafe circuit drives the output to a logic high state. (Contact TI for a logic low failsafe option).

These devices may be powered from either 3.3-V or 5-V supplies on either side in any 3.3-V / 3.3-V, 5-V / 5-V, 5-V / 3.3-V, or 3.3-V / 5-V combination. Note that the signal input pins are 5-V tolerant regardless of the voltage supply level being used.

These devices are characterized for operation over the ambient temperature range of -40°C to 125°C.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

FUNCTION DIAGRAM



Table 1. Device Function Table ISO724x ⁽¹⁾

V _{CC1}	V _{CC2}	INPUT (IN)	OUTPUT ENABLE (EN)	OUTPUT (OUT)
	H H or Open L H or Open		H or Open	Н
DU			H or Open	L
PU	FU	Х	L	Z
		Open	H or Open	Н
PD	PU	Х	H or Open	Н
PD	PU	Х	L	Z

(1) PU = Powered Up; PD = Powered Down ; X = Irrelevant; H = High Level; L = Low Level



		/((/()))			
PRODUCT	SIGNALING RATE	INPUT THRESHOLD	CHANNEL CONFIGURATION	MARKED AS	ORDERING NUMBER
	1 Mbps	~1.5 V (TTL)		19072404	ISO7240ADW (rail)
1307240ADW		(CMOS compatible)		1307240A	ISO7240ADWR (reel)
	25 Mbpo	~1.5 V (TTL)	4/0	18072400	ISO7240CDW (rail)
13072400DW	25 10005	(CMOS compatible)	4/0	13072400	ISO7240CDWR (reel)
	150 Mbpa			180724014	ISO7240MDW (rail)
1307240101000		VCC/2 (CIVIOS)		1307240101	ISO7240MDWR (reel)
	1 Mhna	~1.5 V (TTL)		10070444	ISO7241ADW (rail)
1507241ADVV	r imps	(CMOS compatible)		1507241A	ISO7241ADWR (reel)
100724400\/(1)	OF Mhno	~1.5 V (TTL)	2/4	10070440	ISO7241CDW (rail)
15072410000	25 Mbps	(CMOS compatible)	3/1	15072410	ISO7241CDWR (reel)
	150 Mhna			180724414	ISO7241MDW (rail)
150724 HVIDVV (*)		VCC/2 (CIVIOS)		1507241M	ISO7241MDWR (reel)
	4 Mhma	~1.5 V (TTL)		10070404	ISO7242ADW (rail)
1507242ADVV	r imps	(CMOS compatible)		1507242A	ISO7242ADWR (reel)
	OF Mhno	~1.5 V (TTL)	2/2	10070400	ISO7242CDW (rail)
1507242CDVV	25 Mbps	(CMOS compatible)	2/2	15072420	ISO7242CDWR (reel)
	150 Mhna			180724214	ISO7242MDW (rail)
1307242101000				130724211	ISO7242MDWR (reel)

AVAILABLE OPTIONS

(1) Product Preview



ABSOLUTE MAXIMUM RATINGS⁽¹⁾

					VALUE	UNIT	
V_{CC}	Supply voltag	ge ⁽²⁾ , V _{CC1} , V _{CC2}			–0.5 to 6	V	
VI	Voltage at IN	, OUT, EN			–0.5 to 6	V	
I _O	Output current Human Body Model JEDEC Standard 22. Test Method A114-C.01				±15	mA	
		Human Body Model	JEDEC Standard 22, Test Method A114-C.01		±4		
ESD	Electrostatic discharge	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1	kV	
		Machine Model	ANSI/ESDS5.2-1996		±200	V	
TJ	Maximum jur		170	°C			

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values are with respect to network ground terminal and are peak voltage values.

RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
V			4.5		5.5	V
vcc	Supply voltage, v _{CC1} , v _{CC2}		3		3.6	v
I _{OH}	High-level output current				4	mA
I _{OL}	Low-level output current		-4			mA
		ISO724xA	1			μs
t _{ui}	Input pulse width	ISO724xC	40			~~
		ISO724xM	6.67	5		ns
		ISO724xA	0	250	1000	kbps
1/t _{ui}	Signaling rate	ISO724xC	0	30 ⁽¹⁾	25	Mhaa
		ISO724xM	0	200 ⁽¹⁾	150	Rindba
VIH	High-level input voltage (IN)	180724-14	0.7 V _{CC}		V _{CC}	V
VIL	Low-level input voltage (IN)	150724xM	0		0.3 V _{CC}	V
VIH	High-level input voltage (IN) (EN on all devices)	150724-4 150724-0	2		V _{CC}	V
VIL	Low-level input voltage (IN) (EN on all devices)	- ISO724XA, ISO724XC	0		0.8	V
TJ	Junction temperature			150	°C	
Н	External magnetic field-strength immunity per IEC	61000-4-8 & IEC 61000-4-9 certification			1000	A/m

(1) Typical value at room temperature and well-regulated power supply.



ELECTRICAL CHARACTERISTICS

 V_{CC1} and V_{CC2} at 5-V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT						
	ISO7240A/C/M	Quiescent			1	3	
	ISO7240A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load,		1	3	mA
	ISO7240C/M	25 Mbps			7	10.5	
	ISO7241A/C/M	Quiescent				TBD	
I _{CC1}	ISO7241A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, EN, at 3 V, EN, at 3 V			TBD	mA
	ISO7241C/M	25 Mbps	- Liv ₁ at 3 v, Liv ₂ at 3 v			TBD	
	ISO7242A/C/M	Quiescent				TBD	
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load,			TBD	mA
	ISO7242C/M	25 Mbps				TBD	
	ISO7240A/C/M	Quiescent			15	22	
	ISO7240A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load,		16	22	mA
	ISO7240C/M	25 Mbps			17	25	
	ISO7241A/C/M	Quiescent				TBD	mA
I _{CC2}	ISO7241A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, EN, at 3 V, EN, at 3 V			TBD	
	ISO7241C/M	25 Mbps				TBD	
	ISO7242A/C/M	Quiescent				TBD	
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load,			TBD	mA
	ISO7242C/M	25 Mbps				TBD	
ELECTR	ICAL CHARACTERISTICS						
I _{OFF}	Sleep mode output current		EN at VCC, Single channel		0		μA
V			I _{OH} = -4 mA, See Figure 1	$V_{CC} - 0.4$			V
VOH	High-level output voltage		$I_{OH} = -20 \ \mu A$, See Figure 1	V _{CC} - 0.1			V
\/			I _{OL} = 4 mA, See Figure 1			0.4	
VOL	Low-level output voltage		I _{OL} = 20 μA, See Figure 1			0.1	v
V _{I(HYS)}	Input voltage hysteresis				150		mV
I _{IH}	High-level input current		IN from 0 1/ to 1/			10	
I _{IL}	Low-level input current			-10			μΑ
CI	Input capacitance to ground	ł	IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$		1		pF
CMTI	Common-mode transient in	nmunity	$V_{I} = V_{CC}$ or 0 V, See Figure 4	25	50		kV/µs

SWITCHING CHARACTERISTICS

V_{CC1} and V_{CC2} at 5-V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	100704-4		40		80	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	150724XA				10	
t _{PLH} , t _{PHL}	Propagation delay	100704-0		18		42	ns
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	150724xC				2.5	
t _{PLH} , t _{PHL}	Propagation delay			10		22	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	150724XIVI			1	2	ns
	Port to port elever $\binom{2}{2}$	ISO724xA/C				9	ns
lsk(pp)	p) Part-to-part skew V=7				0		
t	k(o) Channel-to-channel output skew ⁽³⁾	ISO724xA/C				2	ns
lsk(o)		ISO724xM			0	1	
t _r	Output signal rise time		See Figure 1		2		~~
t _f	Output signal fall time				2		ns
t _{PHZ}	Propagation delay, high-level-to-high-imp	edance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-hig	gh-level output	See Figure 2		15	20	~~
t _{PLZ}	Propagation delay, low-level-to-high-impe	dance output			15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low	w-level output			15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		12		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps NRZ data input, Same polarity input on all channels, See Figure 5		1		ns

(1) Also referred to as pulse skew.

(1) Also referred to as pulse skew.
 (2) t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.
 (3) t_{sk(o)} is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

6

Copyright © 2007, Texas Instruments Incorporated



ELECTRICAL CHARACTERISTICS

 V_{CC1} at 5-V, V_{CC2} at 3.3-V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
SUPPLY	Y CURRENT		·					
	ISO7240A/C/M	Quiescent				1	3	
	ISO7240A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, I	EN ₂ at 3 V		1	3	mA
	ISO7240C/M	25 Mbps	-			7	10.5	
	ISO7241A/C/M	Quiescent					TBD	
I _{CC1}	ISO7241A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, E	EN₁ at 3 V,			TBD	mA
	ISO7241C/M	25 Mbps					TBD	
	ISO7242A/C/M	Quiescent					TBD	mA
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, I	EN ₁ at 3 V,			TBD	
	ISO7242C/M	25 Mbps					TBD	
	ISO7240A/C/M	Quiescent				9.5	15	
	ISO7240A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, I	EN ₂ at 3 V		10	15	mA
	ISO7240C/M	25 Mbps	-			10.5	17	
	ISO7241A/C/M	Quiescent					TBD	
I _{CC2}	ISO7241A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, I	$V_{I} = V_{CC}$ or 0 V, All channels, no load, EN ₁ at 3 V, EN ₂ at 3 V			TBD	mA
-	ISO7241C/M	25 Mbps				TBD		
	ISO7242A/C/M	Quiescent				TBD		
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, I			TBD	mA	
	ISO7242C/M	25 Mbps					TBD	
ELECT	RICAL CHARACTER	RISTICS	-					
I _{OFF}	Sleep mode output	t current	EN at VCC, Single channel			0		μA
				ISO7240	V _{CC} - 0.4			
V _{OH}	High-level output v	oltage	I _{OH} = –4 mA, See Figure 1	ISO724x (5-V side)	V _{CC} – 0.8			V
			$I_{OH} = -20 \ \mu A$, See Figure 1		V _{CC} – 0.1			
V			I _{OL} = 4 mA, See Figure 1				0.4	<i>\</i> /
VOL	Low-level output vo	bitage	I _{OL} = 20 μA, See Figure 1	$I_{OL} = 20 \ \mu$ A, See Figure 1			0.1	V
V _{I(HYS)}	Input voltage hyste	eresis				150		mV
I _{IH}	High-level input cu	rrent					10	
I _{IL}	Low-level input cur	rent	IN from 0 V to V _{CC}		-10			μΑ
CI	Input capacitance t	to ground	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$			1		pF
CMTI	Common-mode tra	nsient immunity	$V_I = V_{CC}$ or 0 V, See Figure 4		25	50		kV/µs



SWITCHING CHARACTERISTICS

V_{CC1} at 5-V, V_{CC2} at 3.3-V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	160724×4		40		80	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	1507248A				11	
t _{PLH} , t _{PHL}	Propagation delay	160724×C	See Figure 1	20		46	ns
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	150724xC	See lighte l			3	
t _{PLH} , t _{PHL}	Propagation delay	ISO724xM	SO724xM			28	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}				1	2	ns
t		ISO724xA/C				7.5	ns
t _{sk(pp)}	Pan-to-pan skew	ISO724xM			0		
t _{sk(o)}	Channel to channel output show (3)	ISO724xA/C				2.5	ns
	Channel-to-channel output skew (*)	ISO724xM			0	1	
t _r	Output signal rise time		See Figure 1		2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-impedation	ance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-high-	level output			15	20	
t _{PLZ}	Propagation delay, low-level-to-high-impeda	nce output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-level output				15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		18		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps PRBS NRZ data input, Same polarity input on all channels, See Figure 5		1		ns

(1) Also known as pulse skew

(2)

Also known as pulse skew $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(o)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads. (3)



ELECTRICAL CHARACTERISTICS

 V_{CC1} at 3.3-V, V_{CC2} at 5-V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
SUPPLY	CURRENT							
	ISO7240A/C/M	Quiescent				0.5	1	
	ISO7240A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load,	EN ₂ at 3 V		1	2	mA
	ISO7240C/M	25 Mbps	_			3	5	
	ISO7241A/C/M	Quiescent					TBD	
I _{CC1}	ISO7241A	1 Mbps	$\nabla_{I} = V_{CC}$ or 0 V, All channels, no load, EN ₂ at 3 V	EN ₁ at 3 V,			TBD	mA
	ISO7241C/M	25 Mbps					TBD	
	ISO7242A/C/M	Quiescent					TBD	
	ISO7242A	1 Mbps	$\nabla_{I} = V_{CC}$ or 0 V, All channels, no load, EN ₂ at 3 V	EN ₁ at 3 V,			TBD	mA
	ISO7242C/M	25 Mbps					TBD	
	ISO7240A/C/M	Quiescent				15	22	
	ISO7240A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no load,	EN ₂ at 3 V		16	22	mA
	ISO7240C/M	25 Mbps				17	25	
	ISO7241A/C/M	Quiescent					TBD	
I _{CC2}	ISO7241A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, EN ₂ at 3 V	EN ₁ at 3 V,			TBD	mA
	ISO7241C/M	25 Mbps					TBD	
	ISO7242A/C/M	Quiescent	uiescent				TBD	
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load, EN ₂ at 3 V			TBD	mA	
	ISO7242C/M	25 Mbps					TBD	
ELECTR	RICAL CHARACTER	ISTICS						
I _{OFF}	Sleep mode outpu	ut current	EN at VCC, Single channel			0		μΑ
				ISO7240	$V_{CC} - 0.4$			
V _{OH}	High-level output	voltage	I _{OH} = -4 mA, See Figure 1	ISO724x (5-V side)	V _{CC} – 0.8			V
			$I_{OH} = -20 \ \mu A$, See Figure 1		V _{CC} – 0.1			
V		oltago	I _{OL} = 4 mA, See Figure 1				0.4	V
VOL		ollage	$I_{OL} = 20 \ \mu A$, See Figure 1				0.1	v
V _{I(HYS)}	Input voltage hyst	eresis				150		mV
I _{IH}	High-level input c	urrent	IN from 0 1/ to 1/2 -				10	
IIL	Low-level input cu	irrent			-10			μΑ
CI	Input capacitance	to ground	IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$			1		pF
CMTI	Common-mode tra	ansient	$V_I = V_{CC}$ or 0 V, See Figure 4		25	50		kV/µs

SWITCHING CHARACTERISTICS

V_{CC1} at 3.3-V and V_{CC2} at 5-V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	100704×4		40		80	
PWD	Pulse-width distortion ⁽¹⁾ $ t_{PHL} - t_{PLH} $	150724XA				11	
t _{PLH} , t _{PHL}	Propagation delay	10070420		22		51	ns
PWD	Pulse-width distortion ⁽¹⁾ $ t_{PHL} - t_{PLH} $	150724XC	See Figure 1			3	
t _{PLH} , t _{PHL}	Propagation delay	100704-14		12		26	
PWD	Pulse-width distortion ⁽¹⁾ $ t_{PHL} - t_{PLH} $	150724XM			1	2	ns
	Dent to reat allow (2)	ISO724xA/C				10	
t _{sk(pp)}	Pan-to-part skew	ISO724xM			0		ns
(a)	ISO724xA/C				2.5		
t _{sk(o)}	Channel-to-channel output skew	ISO724xM			0	1	ns
t _r	Output signal rise time		See Figure 1	2			
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-impe	dance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-hig	n-level output			15	20	
t _{PLZ}	Propagation delay, low-level-to-high-imped	lance output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-level output				15	20	
t _{fs}	Failsafe output delay time from input powe	r loss	See Figure 3		12		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps NRZ data input, Same polarity input on all channels, See Figure 5		1		ns

Also known as pulse skew (1)

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(o)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the (2)

(3) same direction while driving identical specified loads.



ELECTRICAL CHARACTERISTICS

 V_{CC1} and V_{CC2} at 3.3 V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT						
	ISO7240A/C/M	Quiescent			0.5	1	
	ISO7240A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, all channels, no load,		1	2	mA
	ISO7240C/M	25 Mbps			3	5	
	ISO7241A/C/M	Quiescent				TBD	
I _{CC1}	ISO7241A	1 Mbps	$V_1 = V_{CC}$ or 0 V, all channels, no load, EN, at 3 V, EN, at 3 V			TBD	
	ISO7241C/M	25 Mbps				TBD	
	ISO7242A/C/M	Quiescent				TBD	mA
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, all channels, no load, EN ₄ at 3 V, EN ₂ at 3 V			TBD	-
	ISO7242C/M	25 Mbps				TBD	
	ISO7240A/C/M	Quiescent			9.5	15	
	ISO7240A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, all channels, no load, EN ₂ at 3 V		10	15	mA
	ISO7240C/M	25 Mbps			10.5	17	I
I _{CC2}	ISO7241A/C/M	Quiescent				TBD	
	ISO7241A	1 Mbps	$V_1 = V_{CC}$ or 0 V, all channels, no load, EN, at 3 V, EN, at 3 V			TBD	
	ISO7241C/M	25 Mbps				TBD	
	ISO7242A/C/M	Quiescent				TBD	mA
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, all channels, no load, EN, at 3 V, EN, at 3 V			TBD	
	ISO7242C/M	25 Mbps				TBD	
ELECTRI	CAL CHARACTERISTICS						
I _{OFF}	Sleep mode output current		EN at V _{CC} , single channel		0		μA
V			I _{OH} = -4 mA, See Figure 1	$V_{CC} - 0.4$			V
∨он	High-level output voltage		$I_{OH} = -20 \ \mu A$, See Figure 1	$V_{CC} - 0.1$			v
V			I _{OL} = 4 mA, See Figure 1			0.4	V
VOL	Low-level output voltage		I _{OL} = 20 μA, See Figure 1			0.1	v
V _{I(HYS)}	Input voltage hysteresis				150		mV
IIH	High-level input current		IN from 0 V or V			10	
IIL	Low-level input current			-10			μΑ
Cı	Input capacitance to ground		IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$		1		pF
CMTI	Common-mode transient immuni	ty	$V_1 = V_{CC}$ or 0 V, See Figure 4	25	50		kV/µs

SWITCHING CHARACTERISTICS

V_{CC1} and V_{CC2} at 3.3-V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	180724×4		45		85	
PWD	Pulse-width distortion $ t_{PHL} - t_{PLH} ^{(1)}$	13072484				12	
t _{PLH} , t _{PHL}	Propagation delay	100704-0		25		56	ns
PWD	Pulse-width distortion $ t_{PHL} - t_{PLH} ^{(1)}$	150724xC	See Figure 1			4	
t _{PLH} , t _{PHL}	Propagation delay	100704-14		12		32	
PWD	Pulse-width distortion $ t_{PHL} - t_{PLH} ^{(1)}$	150724XIVI			1	2	ns
	Port to port elecu(2)	ISO724xA/C				9	22
t _{sk(pp)}	k(pp) Pan-to-pan skew				0		ns
						3	
t _{sk(o)}) Channel-to-channel output skew ⁽³⁾	ISO724xM			0	1	ns
t _r	Output signal rise time	1	- See Figure 1		2		
t _f	Output signal fall time				2		
t _{PHZ}	Propagation delay, high-level-to-high-imped	dance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-high	n-level output			15	20	
t _{PLZ}	Propagation delay, low-level-to-high-imped	ance output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-level output				15	20	
t _{fs}	fs Failsafe output delay time from input power loss		See Figure 3		18		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO724xM	150 Mbps PRBS NRZ data input, same polarity input on all channels, See Figure 5		1		ns

(1) Also referred to as pulse skew.

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads. (2)

(3)

PARAMETER MEASUREMENT INFORMATION



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, Z₀ = 50 Ω .
- B. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within ±20%.

Figure 1. Switching Characteristic Test Circuit and Voltage Waveforms





- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, t_f \leq 3 ns, Z_O = 50 Ω .
- B. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within ±20%.

Figure 2. Enable/Disable Propagation Delay Time Test Circuit and Waveform



PARAMETER MEASUREMENT INFORMATION (continued)



- A. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within ±20%.
- B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, Z_O = 50 Ω .

Figure 3. Failsafe Delay Time Test Circuit and Voltage Waveforms



- A. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within ±20%.
- B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, Z_O = 50 Ω .

Figure 4. Common-Mode Transient Immunity Test Circuit and Voltage Waveform



NOTE: PRBS bit pattern run length is 2¹⁶ – 1. Transition time is 800 ps. NRZ data input has no more than five consecutive 1s or 0s.

Figure 5. Peak-to-Peak Eye-Pattern Jitter Test Circuit and Voltage Waveform



DEVICE INFORMATION

PACKAGE CHARACTERISTICS

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air	7.7			mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	8.1			mm
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
R _{IO}	Isolation resistance	Input to output, V_{IO} = 500 V, all pins on each side of the barrier tied together creating a two-terminal device		>10 ¹²		Ω
CIO	Barrier capacitance Input to output	V _I = 0.4 sin (4E6πt)		1		pF
CI	Input capacitance to ground	V _I = 0.4 sin (4E6πt)		1		pF

DEVICE I/O SCHEMATICS





REGULATORY INFORMATION

UL					
Recognized under 1577 Component Recognition Program ⁽¹⁾					
File Number: E181974					

(1) Production tested \ge 3000 VRMS for 1 second in accordance with UL 1577.

THERMAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
θ_{JA}	Junction-to-air	Low-K Thermal Resistance ⁽¹⁾	168		00000
		High-K Thermal Resistance	96.1		
θ_{JB}	Junction-to-Board Thermal Resistance		61		°C/W
θ_{JC}	Junction-to-Case Thermal Resistance		48		°C/W
PD	Device Power Dissipation	$V_{CC1} = V_{CC2} = 5.5 \text{ V}, \text{ T}_{J} = 150^{\circ}\text{C}, \text{ C}_{L} = 15 \text{ pF},$ Input a 50% duty cycle square wave		220	mW

(1) Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.



TYPICAL CHARACTERISTIC CURVES



TYPICAL CHARACTERISTIC CURVES (continued)



ISO7240 ISO7241 ISO7242 SLLS868-SEPTEMBER 2007



TYPICAL CHARACTERISTIC CURVES (continued)



Copyright © 2007, Texas Instruments Incorporated

APPLICATION INFORMATION



Figure 13. Typical ISO724x Application Circuit

LIFE EXPECTANCY vs. WORKING VOLTAGE



Figure 14. Time-Dependant Dielectric Breakdown Testing Results

TAPE AND REEL BOX INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package	Pins	Site	Reel Diameter (mm)	Reel Width (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7240ADWR	DW	16	SITE 35	330	16	10.9	10.78	3.0	12	16	Q1
ISO7240CDWR	DW	16	SITE 35	330	16	10.9	10.78	3.0	12	16	Q1
ISO7240MDWR	DW	16	SITE 35	330	16	10.9	10.78	3.0	12	16	Q1



PACKAGE MATERIALS INFORMATION

4-Oct-2007



Device	Package	Pins	Site	Length (mm)	Width (mm)	Height (mm)
ISO7240ADWR	DW	16	SITE 35	406.0	348.0	63.0
ISO7240CDWR	DW	16	SITE 35	406.0	348.0	63.0
ISO7240MDWR	DW	16	SITE 35	406.0	348.0	63.0

DW (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AA.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
RFID	www.ti-rfid.com	Telephony	www.ti.com/telephony
Low Power Wireless	www.ti.com/lpw	Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2007, Texas Instruments Incorporated